✓RoHS

RF Power Field Effect Transistors
N‑Channel Enhancement‑Mode Lateral MOSFETs

Designed for CDMA base station applications with frequencies from 1470 to 1510 MHz. Can be used in Class AB and Class C for all typical cellular base station modulations.
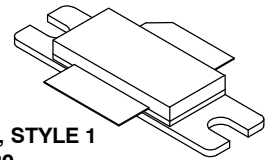
MRF7S15100HR3
MRF7S15100HSR3

1470‑1510 MHz, 23 W AVG., 28 V SINGLE W‑CDMA LATERAL N‑CHANNEL RF POWER MOSFETs

- Typical Single‑Carrier W‑CDMA Performance: V_{DD} = 28 Volts, I_{DQ} = 600 mA, P_{out} = 23 Watts Avg., f = 1507.5 MHz, IQ Magnitude Clipping, Channel Bandwidth = 3.84 MHz, Input Signal PAR = 7.5 dB @ 0.01% Probability on CCDF.
  - Power Gain — 19.5 dB
  - Drain Efficiency — 32%
  - Device Output Signal PAR — 6.2 dB @ 0.01% Probability on CCDF
  - ACPR @ 5 MHz Offset — -38 dBc in 3.84 MHz Channel Bandwidth
- Capable of Handling 10:1 VSWR, @ 32 Vdc, 1490 MHz, 100 Watts CW Output Power
- Typical P_{out} @ 1 dB Compression Point $\simeq$ 100 Watts CW

Features

- 100% PAR Tested for Guaranteed Output Power Capability
- Characterized with Series Equivalent Large‑Signal Impedance Parameters
- Internally Matched for Ease of Use
- Integrated ESD Protection
- Greater Negative Gate‑Source Voltage Range for Improved Class C Operation
- Optimized for Doherty Applications
- RoHS Compliant
- In Tape and Reel. R3 Suffix = 250 Units per 56 mm, 13 inch Reel.

CASE 465‑06, STYLE 1
NI‑780
MRF7S1500HR3
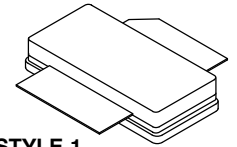
CASE 465A‑06, STYLE 1
NI‑780S
MRF7S1500HSR3

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain‑Source Voltage	V_{DSS}	-0.5, +65	Vdc
Gate‑Source Voltage	V_{GS}	-6.0, +10	Vdc
Operating Voltage	V_{DD}	32, +0	Vdc
Storage Temperature Range	T_{stg}	- 65 to +150	°C
Case Operating Temperature	T_C	150	°C
Operating Junction Temperature [1,2]	T_J	225	°C
CW Operation @ T_A = 25°C Derate above 25°C	CW	75 0.36	W W/°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value [2,3]	Unit

Thermal Resistance, Junction to Case
    Case Temperature 80°C, 55 W CW
    Case Temperature 77°C, 23 W CW
	$R_{\theta JC}$	
		0.65
		0.74
			°C/W

1. Continuous use at maximum temperature will affect MTTF.
2. MTTF calculator available at http://www.freescale.com/rf. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.
3. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers.* Go to http://www.freescale.com/rf. Select Documentation/Application Notes ‑ AN1955.

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Table 3. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JESD22-A114)	1C (Minimum)
Machine Model (per EIA/JESD22-A115)	A (Minimum)
Charge Device Model (per JESD22-C101)	IV (Minimum)

Table 4. Electrical Characteristics (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Off Characteristics					
Zero Gate Voltage Drain Leakage Current (V_{DS} = 65 Vdc, V_{GS} = 0 Vdc)	I_{DSS}	—	—	10	μAdc
Zero Gate Voltage Drain Leakage Current (V_{DD} = 28 Vdc, V_{GS} = 0 Vdc)	I_{DSS}	—	—	1	μAdc
Gate-Source Leakage Current (V_{GS} = 5 Vdc, V_{DS} = 0 Vdc)	I_{GSS}	—	—	1	μAdc
On Characteristics					
Gate Threshold Voltage (V_{DS} = 10 Vdc, I_D = 174 μAdc)	$V_{GS(th)}$	1.2	2	2.7	Vdc
Gate Quiescent Voltage (V_{DD} = 28 Vdc, I_D = 600 mAdc, Measured in Functional Test)	$V_{GS(Q)}$	2	2.7	3.5	Vdc
Drain-Source On-Voltage (V_{GS} = 10 Vdc, I_D = 1.74 Adc)	$V_{DS(on)}$	0.1	0.2	0.3	Vdc
Dynamic Characteristics [1]					
Reverse Transfer Capacitance (V_{DS} = 28 Vdc ± 30 mV(rms)ac @ 1 MHz, V_{GS} = 0 Vdc)	C_{rss}	—	0.6	—	pF
Output Capacitance (V_{DS} = 28 Vdc ± 30 mV(rms)ac @ 1 MHz, V_{GS} = 0 Vdc)	C_{oss}	—	300	—	pF
Input Capacitance (V_{DS} = 28 Vdc, V_{GS} = 0 Vdc ± 30 mV(rms)ac @ 1 MHz)	C_{iss}	—	176	—	pF

Functional Tests (In Freescale Test Fixture, 50 ohm system) V_{DD} = 28 Vdc, I_{DQ} = 600 mA, P_{out} = 23 W Avg., f = 1507.5 MHz, Single-Carrier W-CDMA, IQ Magnitude Clipping, Input Signal PAR = 7.5 dB @ 0.01% Probability on CCDF. ACPR measured in 3.84 MHz Channel Bandwidth @ ±5 MHz Offset.

Characteristic	Symbol	Min	Typ	Max	Unit
Power Gain	G_{ps}	18	19.5	21	dB
Drain Efficiency	η_D	30	32	—	%
Output Peak-to-Average Ratio @ 0.01% Probability on CCDF	PAR	5.9	6.2	—	dB
Adjacent Channel Power Ratio	ACPR	—	-38	-35	dBc
Input Return Loss	IRL	—	-15	-8	dB

1. Part internally matched both on input and output.

(continued)

Table 4. Electrical Characteristics $(T_A = 25°C$ unless otherwise noted) **(continued)**

Characteristic	Symbol	Min	Typ	Max	Unit
Typical Performances (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 28$ Vdc, $I_{DQ} = 600$ mA, 1470 - 1510 MHz Bandwidth					
P_{out} @ 1 dB Compression Point, CW	P1dB	—	100	—	W
IMD Symmetry @ 90 W PEP, P_{out} where IMD Third Order Intermodulation $\cong$ 30 dBc (Delta IMD Third Order Intermodulation between Upper and Lower Sidebands > 2 dB)	IMD_{sym}	—	40	—	MHz
VBW Resonance Point (IMD Third Order Intermodulation Inflection Point)	VBW_{res}	—	70	—	MHz
Gain Flatness in 40 MHz Bandwidth @ $P_{out} = 23$ W Avg.	G_F	—	0.2	—	dB
Average Deviation from Linear Phase in 40 MHz Bandwidth @ $P_{out} = 100$ W CW	Φ	—	4.5	—	°
Average Group Delay @ $P_{out} = 100$ W CW, f = 1490 MHz	Delay	—	1.9	—	ns
Part-to-Part Insertion Phase Variation @ $P_{out} = 100$ W CW, f = 1490 MHz, Six Sigma Window	ΔΦ	—	23	—	°
Gain Variation over Temperature (-30°C to +85°C)	ΔG	—	0.010	—	dB/°C
Output Power Variation over Temperature (-30°C to +85°C)	ΔP1dB	—	0.007	—	W/°C
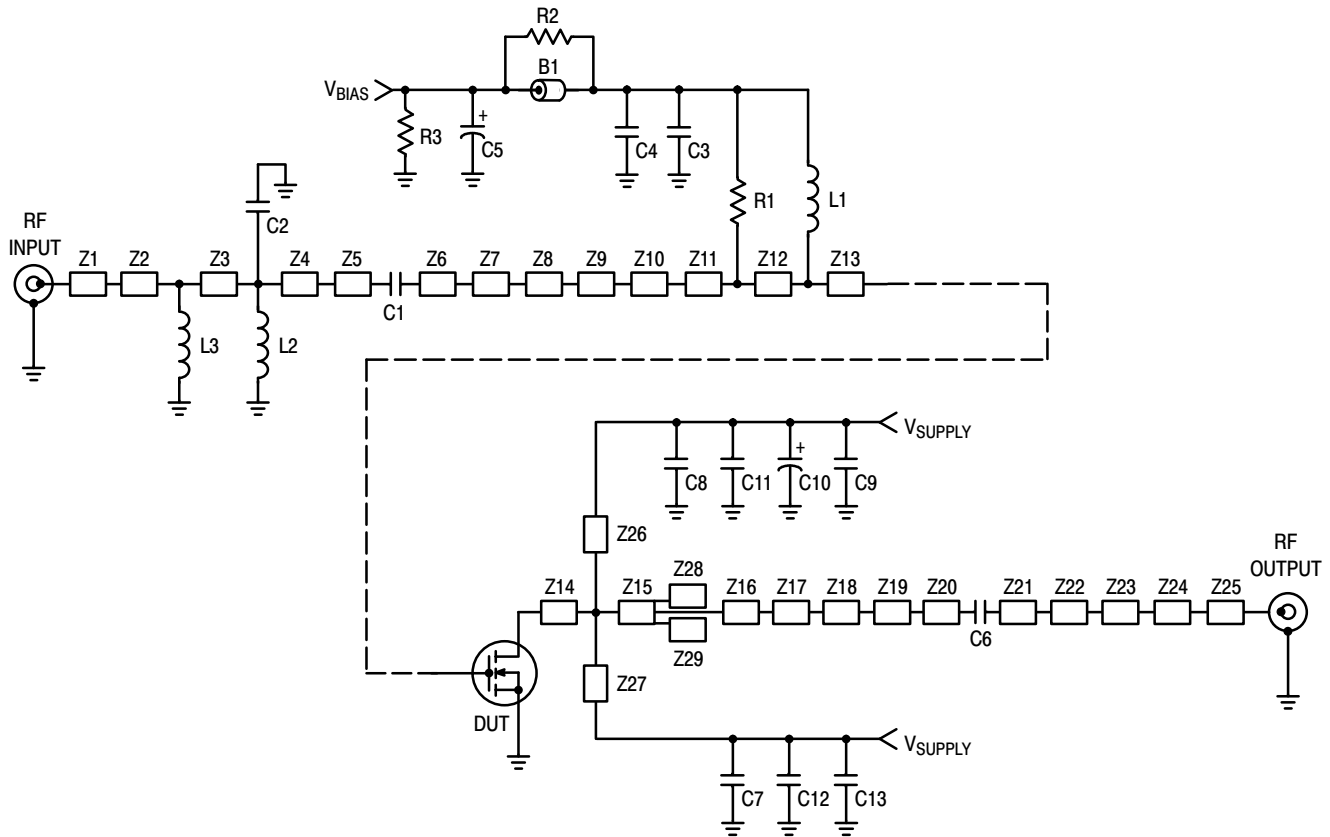
Z1   0.084″ x 0.078″ Microstrip   Z15   1.330″ x 0.538″ Microstrip
Z2   0.149″ x 0.153″ Microstrip   Z16   0.270″ x 0.280″ Microstrip
Z3   0.149″ x 0.303″ Microstrip   Z17   0.187″ x 0.150″ Microstrip
Z4   0.149″ x 0.065″ Microstrip   Z18   0.084″ x 0.042″ Microstrip
Z5   0.084″ x 0.146″ Microstrip   Z19   0.184″ x 0.292″ Microstrip
Z6   0.084″ x 0.104″ Microstrip   Z20   0.084″ x 0.066″ Microstrip
Z7   0.218″ x 0.080″ Microstrip   Z21   0.886″ x 0.194″ Microstrip
Z8   0.084″ x 0.206″ Microstrip   Z22   0.300″ x 0.084″ Microstrip
Z9   0.224″ x 0.085″ Microstrip   Z23   0.084″ x 0.215″ Microstrip
Z10   0.084″ x 0.369″ Microstrip   Z24   0.221″ x 0.075″ Microstrip
Z11   1.288″ x 0.206″ Microstrip   Z25   0.084″ x 0.175″ Microstrip
Z12   1.288″ x 0.144″ Microstrip   Z26, Z27 0.200″ x 0.525″ Microstrip
Z13   1.288″ x 0.369″ Microstrip   Z28, Z29 0.235″ x 0.102″ Microstrip
Z14   1.330″ x 0.112″ Microstrip   PCB   Arlon CuClad 250GX‑0300‑55‑22, 0.030″, ε_r = 2.55

Figure 1. MRF7S15100HR3(HSR3) Test Circuit Schematic

Table 5. MRF7S15100HR3(HSR3) Test Circuit Component Designations and Values

| Part	Description	Part Number	Manufacturer
B1	Short Ferrite Bead	2743019447	Fair‑Rite
C1, C6, C7, C8	15 pF Chip Capacitors	ATC100B150JT500XT	ATC
C2	0.5 pF Chip Capacitor	ATC100B0R5BT500XT	ATC
C3	10 pF Chip Capacitor	ATC100B100JT500XT	ATC
C4, C9, C13	6.8 µF, 50 V Chip Capacitors	C4532JB1H685MT	TDK
C5, C10	100 µF, 50 V Electrolytic Capacitors	222215371101	Vishay
C11, C12	2.2 µF, 50 V Chip Capacitors	C3225JB2A225MT	TDK
L1, L2, L3	7.15 nH Inductors	1606‑TLC	Coilcraft
R1, R2	100 Ω, 1/4 W Chip Resistors	CRCW12061000FKEA	Vishay
R3	10 KΩ, 1/4 W Chip Resistor	CRCW12061002FKEA	Vishay

MRF7S15100HR3 MRF7S15100HSR3
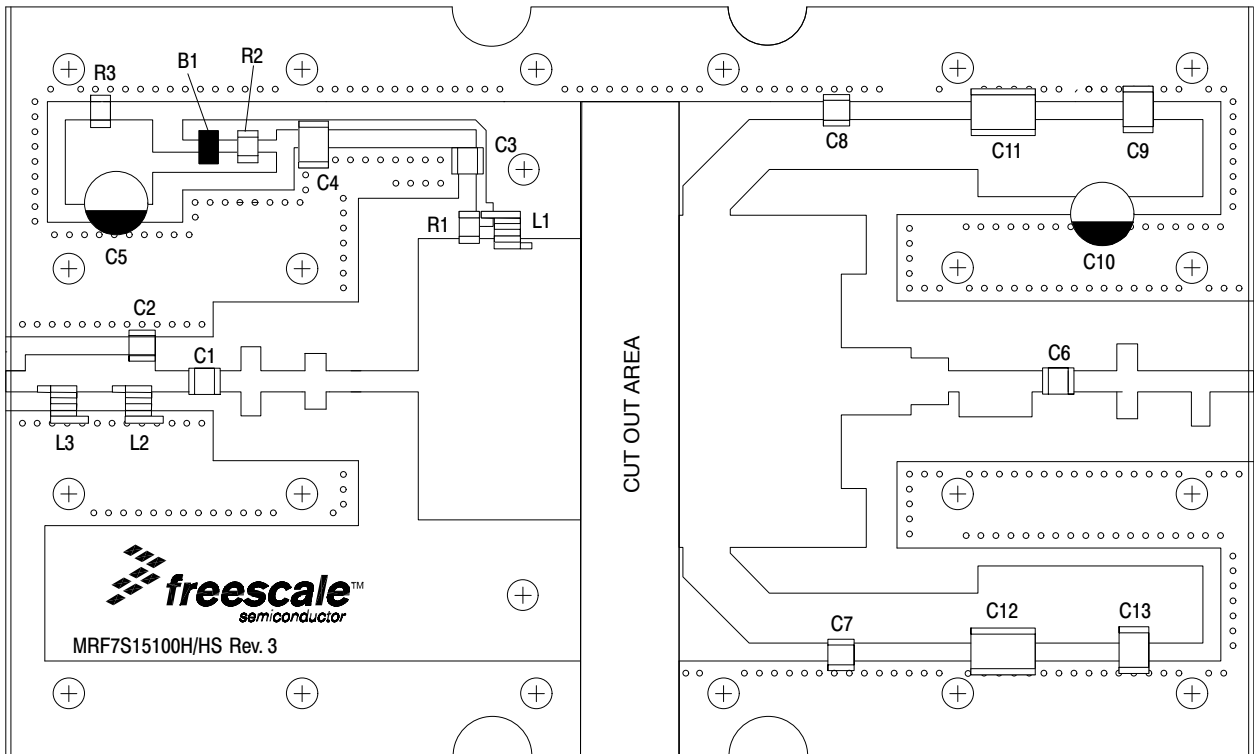
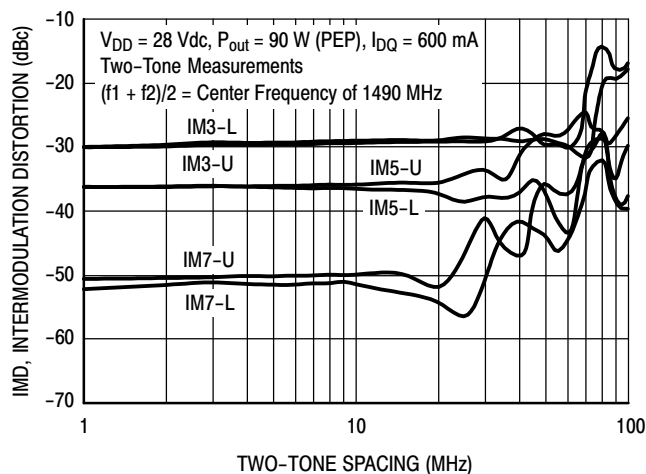**Figure 2. MRF7S15100HR3(HSR3) Test Circuit Component Layout**
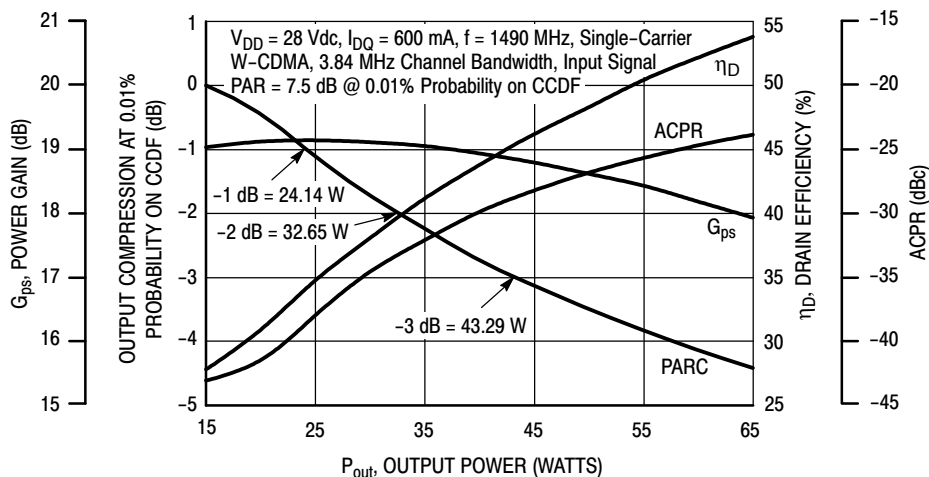
TYPICAL CHARACTERISTICS
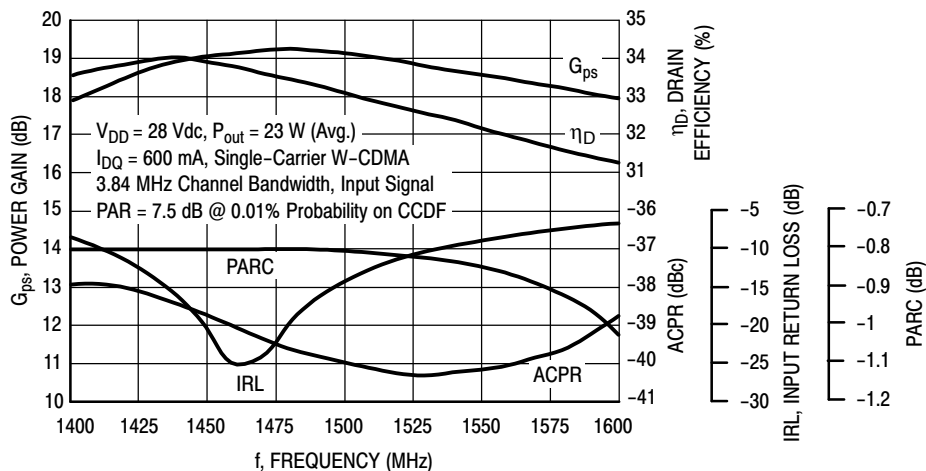
**Figure 3. Output Peak‑to‑Average Ratio Compression (PARC)
Broadband Performance @ P_{out} = 23 Watts Avg.**
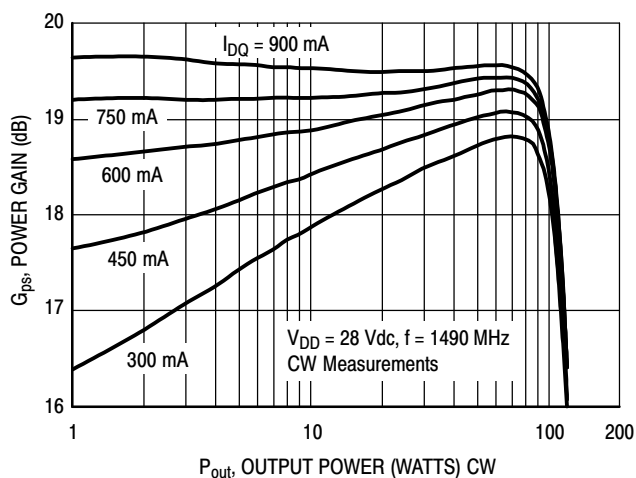
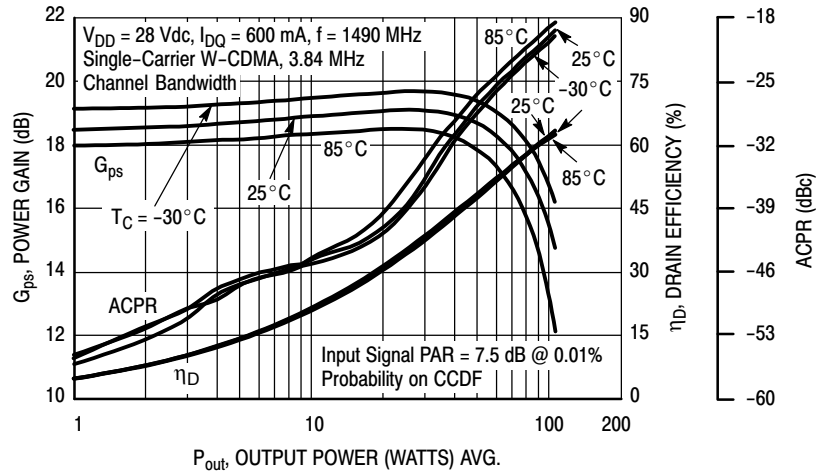**Figure 4. CW Power Gain versus Output Power**

**Figure 5. Intermodulation Distortion Products
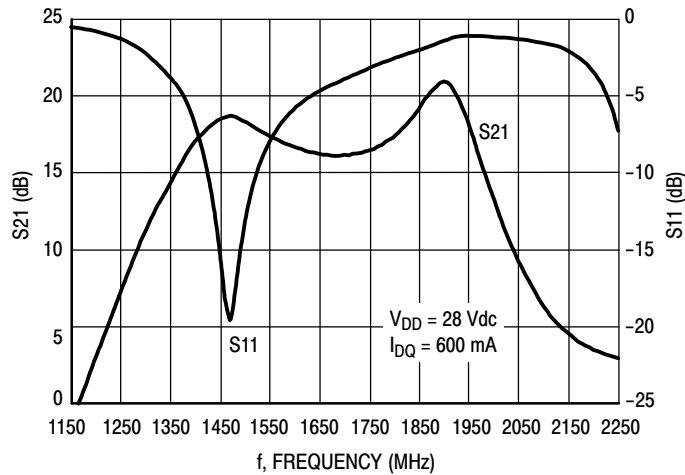versus Tone Spacing**

**Figure 6. Output Peak‑to‑Average Ratio
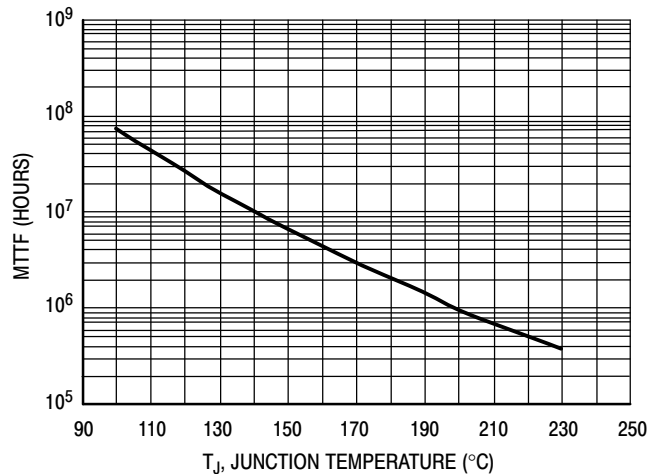Compression (PARC) versus Output Power**

MRF7S15100HR3 MRF7S15100HSR3

TYPICAL CHARACTERISTICS

Figure 7. Single-Carrier W-CDMA Power Gain, Drain Efficiency and ACPR versus Output Power

Figure 8. Broadband Frequency Response

This above graph displays calculated MTTF in hours when the device is operated at V_{DD} = 28 Vdc, P_{out} = 23 W Avg., and η_D = 32%.

MTTF calculator available at http://www.freescale.com/rf. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.

Figure 9. MTTF versus Junction Temperature
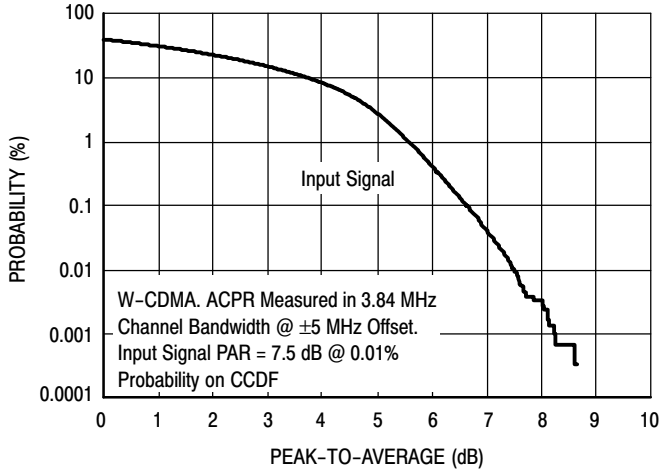
W-CDMA TEST SIGNAL

Figure 10. CCDF W-CDMA IQ Magnitude Clipping, Single-Carrier Test Signal
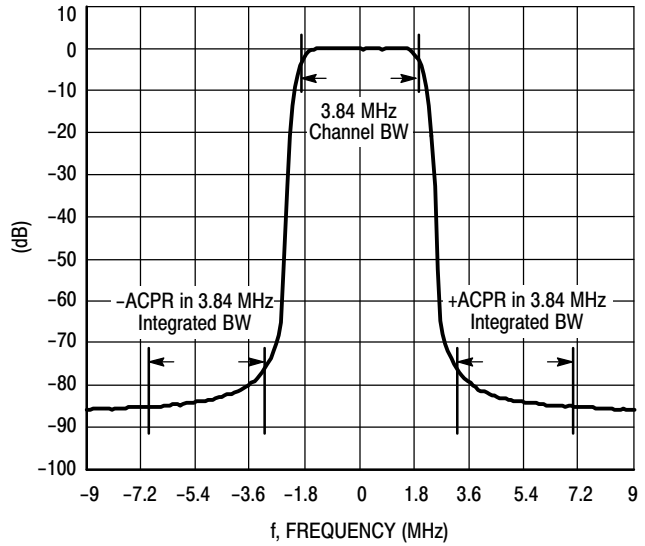
Figure 11. Single-Carrier W-CDMA Spectrum
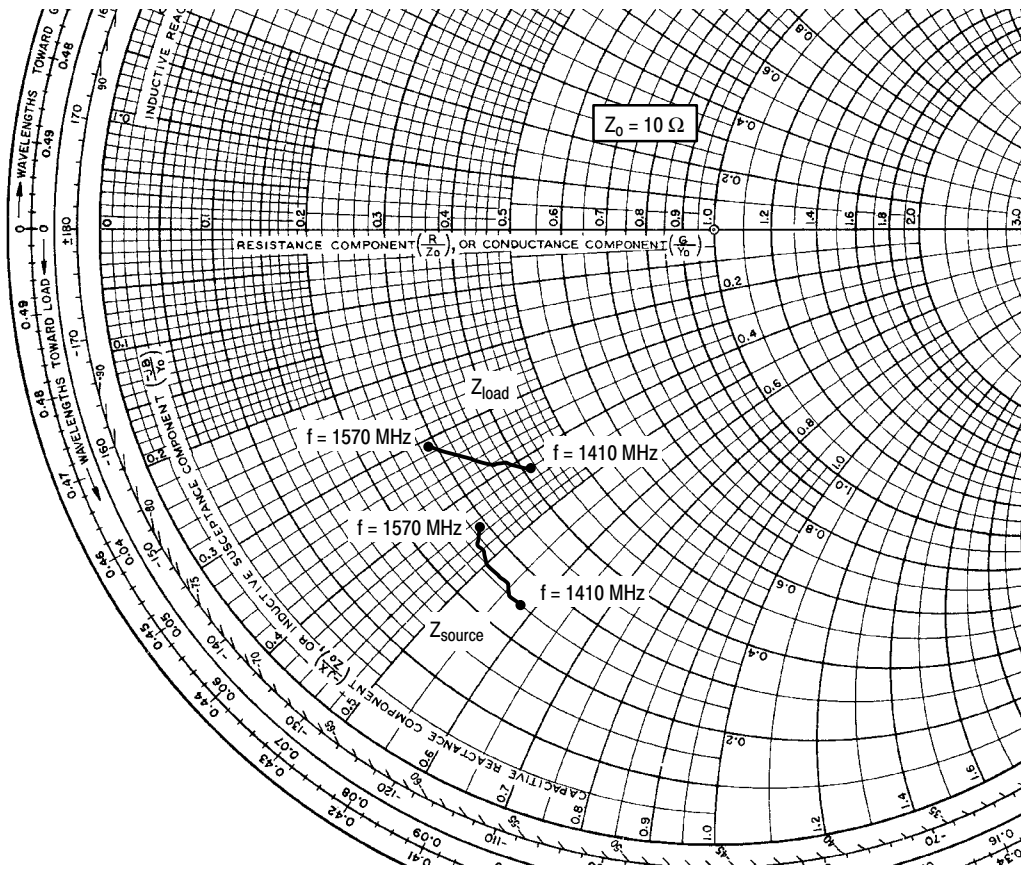
V_{DD} = 28 Vdc, I_{DQ} = 600 mA, P_{out} = 23 W Avg.

f MHz	Z_{source} Ω	Z_{load} Ω
1410	2.51 - j5.82	4.12 - j4.20
1430	2.53 - j5.58	3.95 - j4.07
1450	2.55 - j5.36	3.78 - j3.94
1470	2.58 - j5.15	3.61 - j3.80
1490	2.62 - j4.97	3.45 - j3.65
1510	2.67 - j4.81	3.30 - j3.51
1530	2.73 - j4.68	3.15 - j3.37
1550	2.79 - j4.57	3.00 - j3.22
1570	2.85 - j4.49	2.87 - j3.06

Z_{source} = Test circuit impedance as measured from gate to ground.

Z_{load} = Test circuit impedance as measured from drain to ground.

Input Matching Network

Device Under Test

Output Matching Network
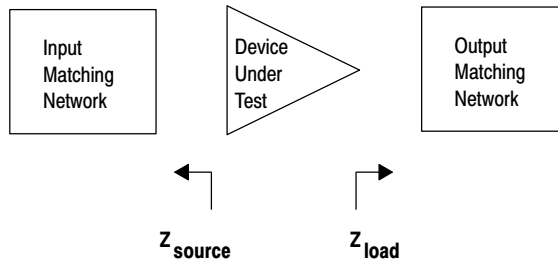
Z_{source} Z_{load}

Figure 12. Series Equivalent Source and Load Impedance
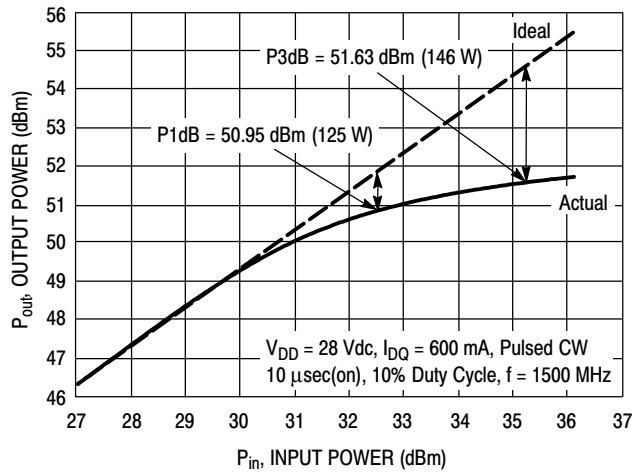
NOTE: Load Pull Test Fixture Tuned for Peak P1dB Output Power @ 28 V

Test Impedances per Compression Level

	Z_{source} Ω	Z_{load} Ω
P1dB	2.02 + j6.21	2.00 - j3.65

**Figure 13. Pulsed CW Output Power
versus Input Power @ 28 V**

PACKAGE DIMENSIONS
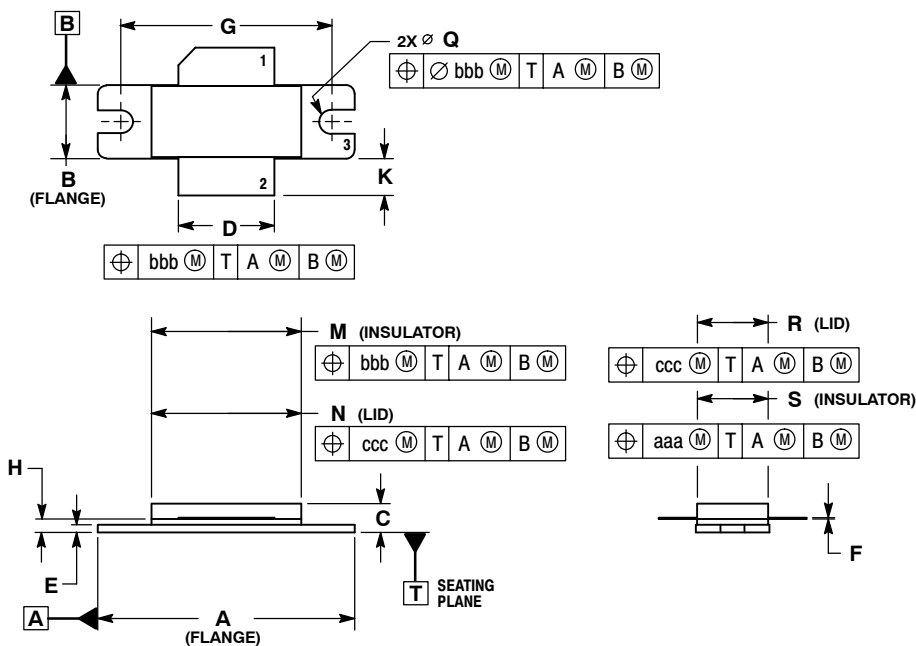
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	1.335	1.345	33.91	34.16
B	0.380	0.390	9.65	9.91
C	0.125	0.170	3.18	4.32
D	0.495	0.505	12.57	12.83
E	0.035	0.045	0.89	1.14
F	0.003	0.006	0.08	0.15
G	1.100 BSC		27.94 BSC	
H	0.057	0.067	1.45	1.70
K	0.170	0.210	4.32	5.33
M	0.774	0.786	19.66	19.96
N	0.772	0.788	19.60	20.00
Q	∅.118	∅.138	∅3.00	∅3.51
R	0.365	0.375	9.27	9.53
S	0.365	0.375	9.27	9.52
aaa	0.005 REF		0.127 REF	
bbb	0.010 REF		0.254 REF	
ccc	0.015 REF		0.381 REF	

STYLE 1:
PIN 1. DRAIN
2. GATE
3. SOURCE

CASE 465-06
ISSUE G
NI-780
MRF7S15100HR3
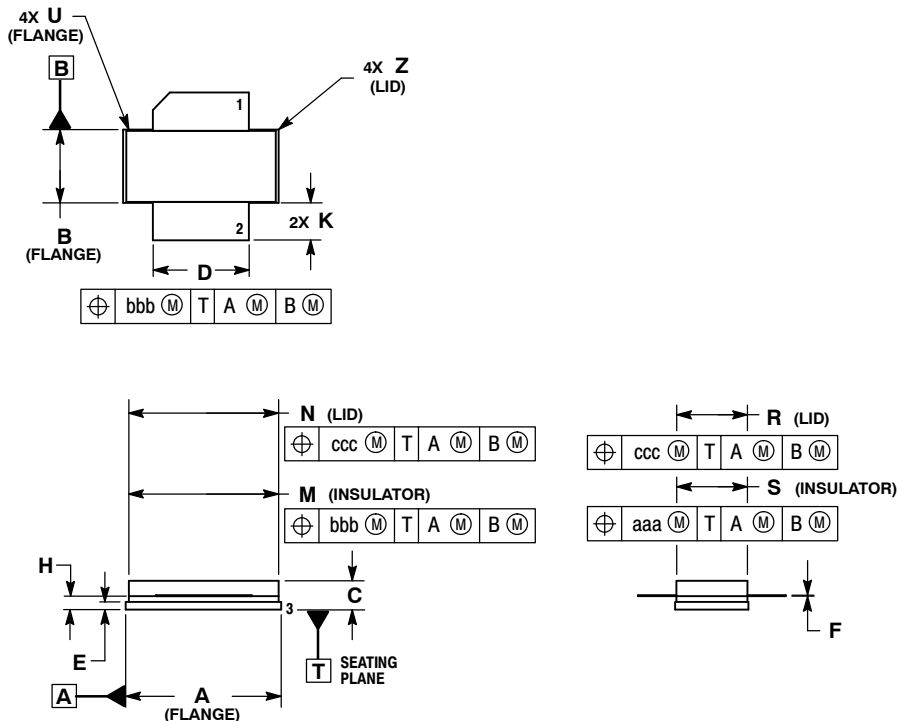
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.805	0.815	20.45	20.70
B	0.380	0.390	9.65	9.91
C	0.125	0.170	3.18	4.32
D	0.495	0.505	12.57	12.83
E	0.035	0.045	0.89	1.14
F	0.003	0.006	0.08	0.15
H	0.057	0.067	1.45	1.70
K	0.170	0.210	4.32	5.33
M	0.774	0.786	19.61	20.02
N	0.772	0.788	19.61	20.02
R	0.365	0.375	9.27	9.53
S	0.365	0.375	9.27	9.52
U	---	0.040	---	1.02
Z	---	0.030	---	0.76
aaa	0.005 REF		0.127 REF	
bbb	0.010 REF		0.254 REF	
ccc	0.015 REF		0.381 REF	

STYLE 1:
PIN 1. DRAIN
2. GATE
5. SOURCE

CASE 465A-06
ISSUE H
NI-780S
MRF7S15100HSR3

PRODUCT DOCUMENTATION, TOOLS AND SOFTWARE

   Refer to the following documents to aid your design process.

Application Notes

• AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Engineering Bulletins

• EB212: Using Data Sheet Impedances for RF LDMOS Devices

Software

• Electromigration MTTF Calculator

• RF High Power Model

For Software and Tools, do a Part Number search at http://www.freescale.com, and select the "Part Number" link. Go to the Software & Tools tab on the part's Product Summary page to download the respective tool.

REVISION HISTORY

   The following table summarizes revisions to this document.

Revision	Date	Description
0	July 2008	• Initial Release of Data Sheet
1	Feb. 2009	• Added Fig. 9, MTTF versus Junction Temperature, p. 7
2	June 2009	• Added Maximum CW limit and temperature derating factor to the Maximum Ratings table, p. 1 • Fig. 10, CCDF W‐CDMA IQ Magnitude Clipping, Single‐Carrier Test Signal and Fig. 11, Single‐Carrier W‐CDMA Spectrum updated to show the undistorted input test signal, p. 8 • Added Electromigration MTTF Calculator and RF High Power Model availability to Product Documentation, Tools and Software, p. 12

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